

Silicon N-Channel Super Junction Power MOSFET

Description

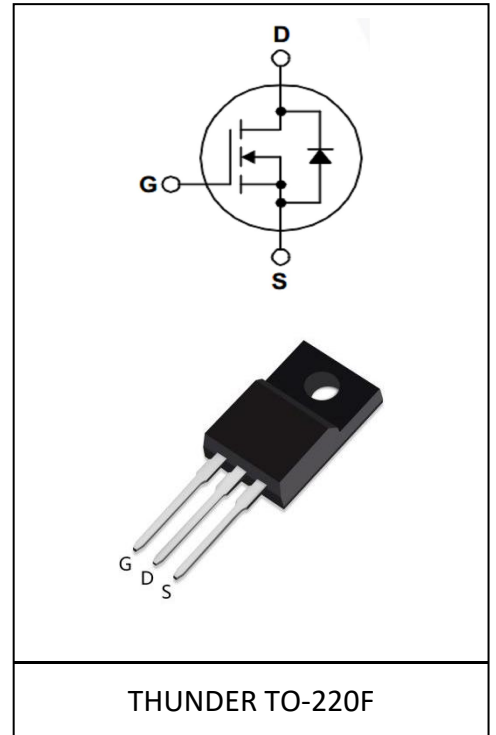
- Very Low FOM ($R_{DS(on)} \times Q_g$)
- Extremely low switching loss
- Excellent stability and uniformity
- 100% Avalanche Tested

Features

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- Motor Control & LED Lighting Power
- DC-DC Converters

Product Summary

V_{DS}	800V
$R_{DS(on),typ}$	0.25 Ω
I_D	18A



Absolute Maximum Ratings $T_C=25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Value	Units
Drain-Source Voltage	V_{DSS}	800	V
Gate-Source Voltage	V_{GS}	± 30	V
Drain Current – Continuous($T_C=25^\circ\text{C}$)	I_D	18*	A
Drain Current – Continuous($T_C=100^\circ\text{C}$)		11*	A
Drain Current – Pulsed (Note 1)	I_{DM}	54*	A
Single Pulsed Avalanche Energy (Note 2)	E_{AS}	300	mJ
MOSFET dv/dt ruggedness, $V_{DS}=0\dots 480\text{V}$	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS}=0\dots 480\text{V}$, $I_{DS} \leq I_D$	dv/dt	15	V/ns
Power Dissipation ($T_C=25^\circ\text{C}$)	P_D	34	W
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ\text{C}$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	T_L	300	$^\circ\text{C}$

* Drain current limited by maximum junction temperature

Thermal Resistance Characteristics

Parameter	Symbol	Max	Units
Junction-to-Case	R_{thJC}	3.6	°C/W
Junction-to-Ambient	R_{thJA}	80	

Electrical Characteristics $T_c=25^{\circ}\text{C}$ unless otherwise specified

Parameter	Symbol	Value			Units	Test Conditions
		min.	typ.	max.		

On Characteristics

Gate Threshold Voltage	V_{GS}	2.5	-	4.5	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	-	0.25	0.29	Ω	$V_{GS} = 10\text{ V}, I_D = 9\text{ A}$

Off Characteristics

Drain-Source Breakdown Voltage	BV_{DSS}	800	-	-	V	$V_{GS} = 0\text{ V}, I_D = 250\mu\text{A}$
Zero Gate Voltage Drain Current	I_{DSS}	-	-	1	μA	$V_{DS} = 800\text{ V}, V_{GS} = 0\text{ V}$
		-	-	100	μA	$V_{DS} = 800\text{ V}, T_J = 125^{\circ}\text{C}$
Gate-Body Leakage Current	I_{GSS}	-	-	± 100	μA	$V_{GS} = \pm 30\text{ V}, V_{DS} = 0\text{ V}$

Dynamic Characteristics

Input Capacitance	C_{iss}	-	1728	-	pF	$V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V},$ $f = 100\text{ kHz}$
Output Capacitance	C_{oss}	-	48	-	pF	
Reverse Transfer Capacitance	C_{rss}	-	0.78	-	pF	
Gate Series Resistance	R_g	-	25	-	Ω	$f=1.0\text{ MHz}$

Switching Characteristics

Turn-On Time	$t_{d(on)}$	-	29	-	ns	$V_{DS} = 400\text{ V}, I_D = 18\text{ A},$ $R_G = 25\Omega$
Turn-On Rise Time	t_r	-	42	-	ns	
Turn-Off Delay Time	$t_{d(off)}$	-	137	-	ns	
Turn-Off Fall Time	t_f	-	36	-	ns	
Total Gate Charge	Q_g	-	39	-	nC	$V_{DS} = 600\text{ V}, I_D = 18\text{ A}$ $V_{GS} = 10\text{ V}$
Gate-Source Charge	Q_{gs}	-	8.6	-	nC	
Gate-Drain Charge	Q_{gd}	-	13.5	-	nC	

Source-Drain Diode Maximum Ratings and Characteristics

Continuous Source-Drain Diode Forward Current	I_S	-	-	18	A	
Pulsed Source-Drain Diode Forward Current	I_{SM}	-	-	54		
Source-Drain Diode Forward Voltage	V_{SD}	-	-	1.3	V	$I_S = 18\text{ A}, V_{GS} = 0\text{ V}$
Reverse Recovery Time	t_{rr}	-	427	-	ns	$I_S = 18\text{ A}, V_{DD} = 400\text{ V}$ $di_F/dt = 100\text{ A}/\mu\text{s}$
Reverse Recovery Charge	Q_{rr}	-	6.8	-	μC	

Notes ;

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $I_{AS}=7.5\text{ A}, V_{DD}=50\text{ V}, R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$
3. $I_{SD}\leq I_D, di/dt\leq 200\text{ A}/\mu\text{s}, V_{DD}\leq BV_{DSS}$, Starting $T_J=25^\circ\text{C}$
4. Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Characteristics

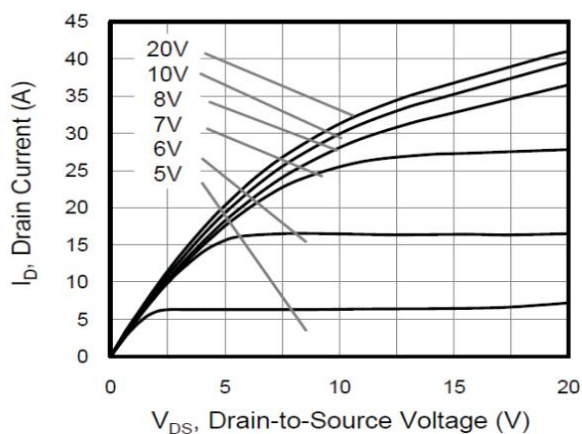


Figure 1. On Region Characteristics

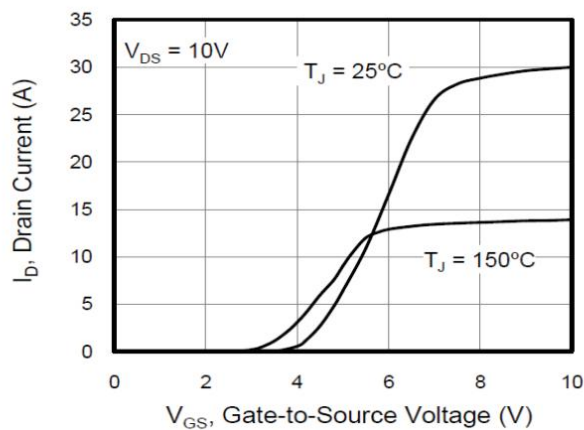


Figure 2. Transfer Characteristics

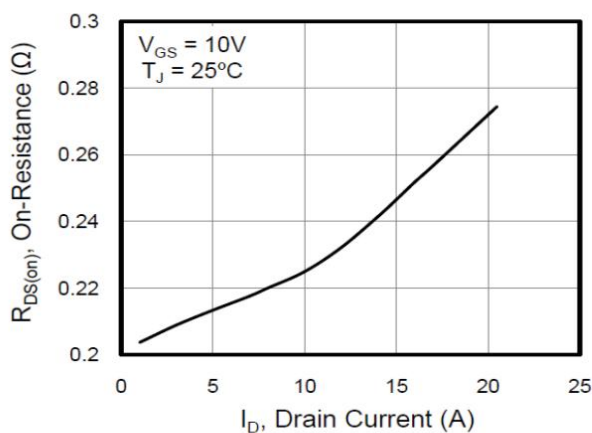


Figure 3. On Resistance Variation vs Drain Current and Gate Voltage

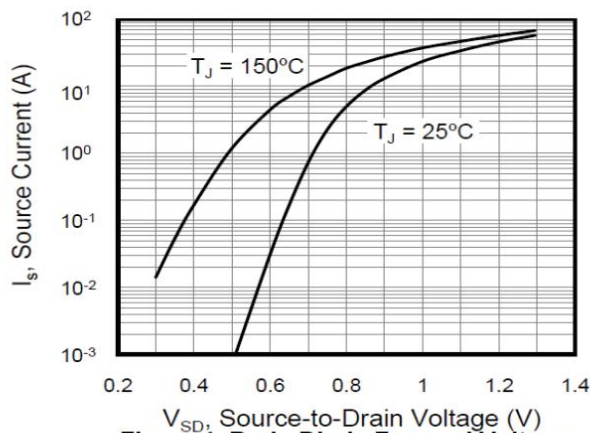


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

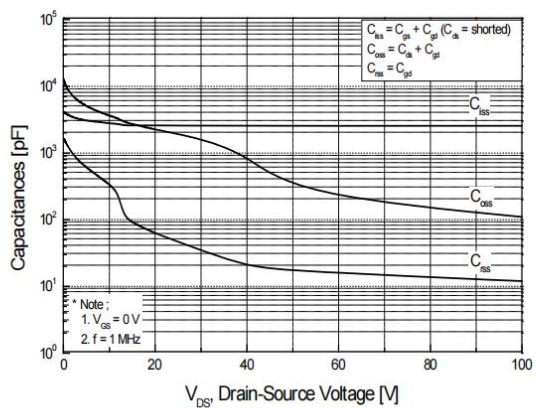


Figure 5. Capacitance Characteristics

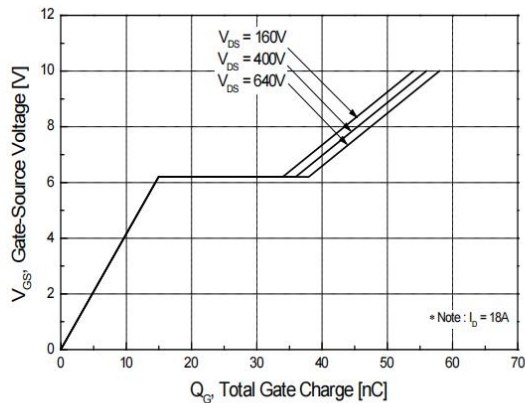


Figure 6. Gate Charge Characteristics

Typical Characteristics (continued)

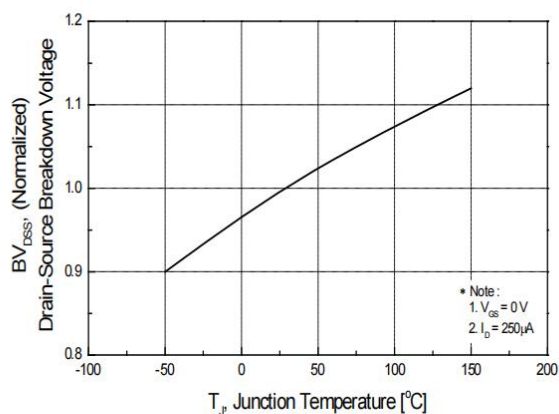


Figure 7. Breakdown Voltage Variation vs Temperature

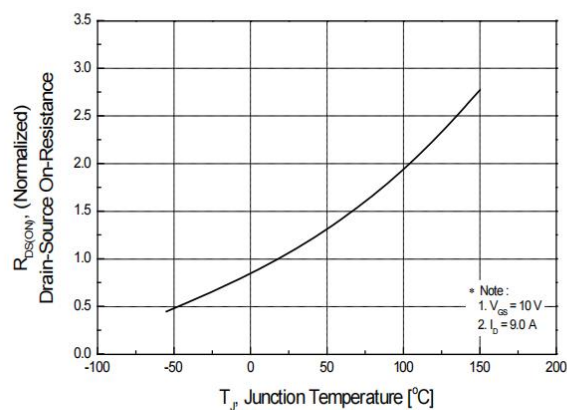


Figure 8. On-Resistance Variation vs Temperature

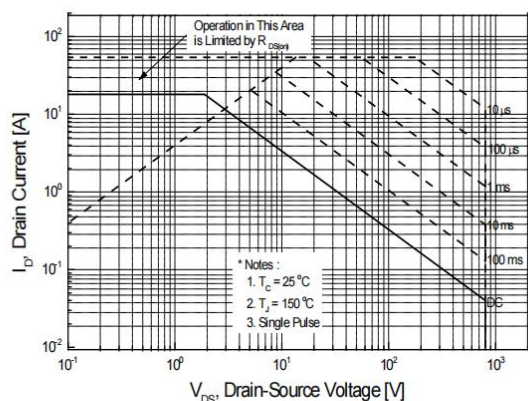


Figure 9. Maximum Safe Operating Area

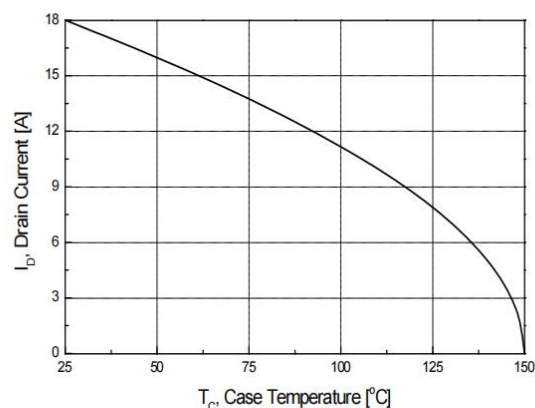


Figure 10. Maximum Drain Current vs Case Temperature

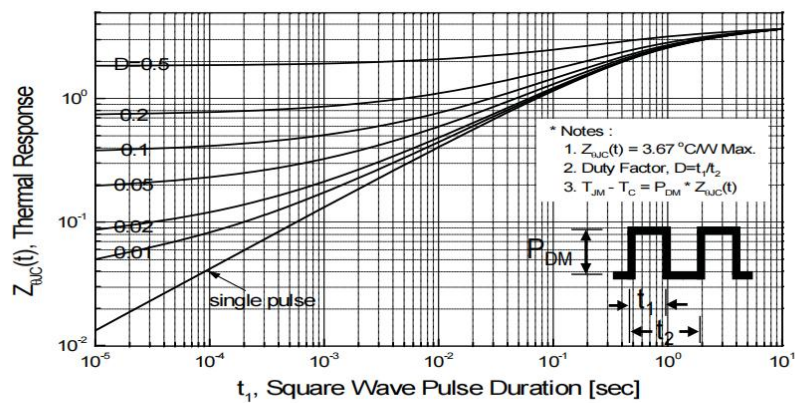


Figure 11. Transient Thermal Response Curve

Fig 12. Gate Charge Test Circuit & Waveform

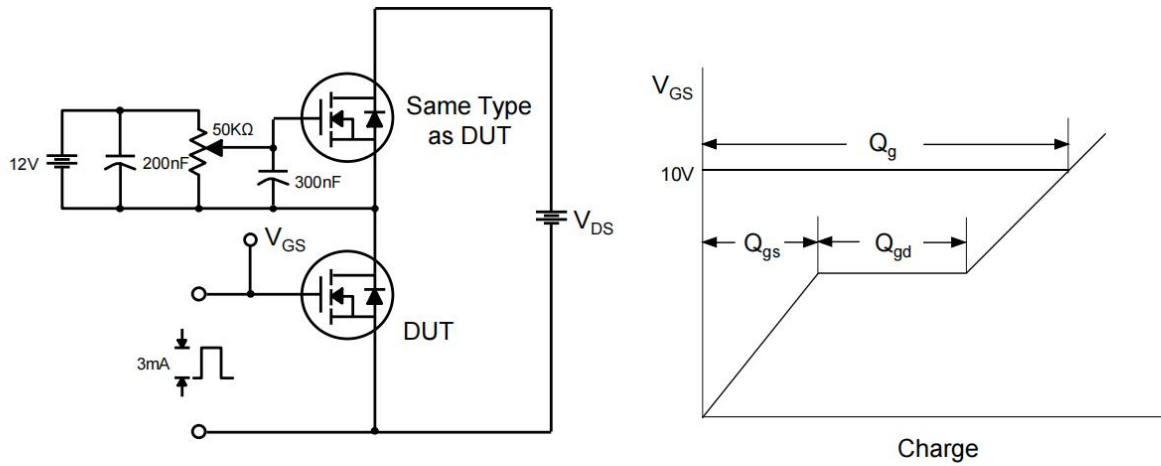


Fig 13. Resistive Switching Test Circuit & Waveforms

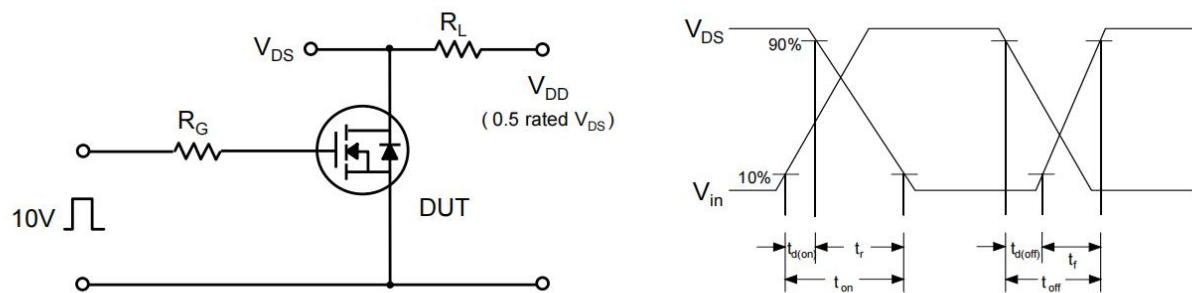


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

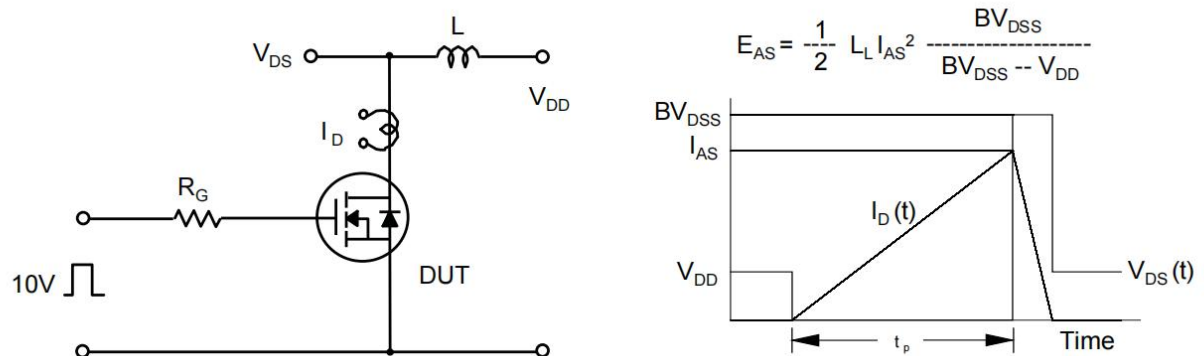
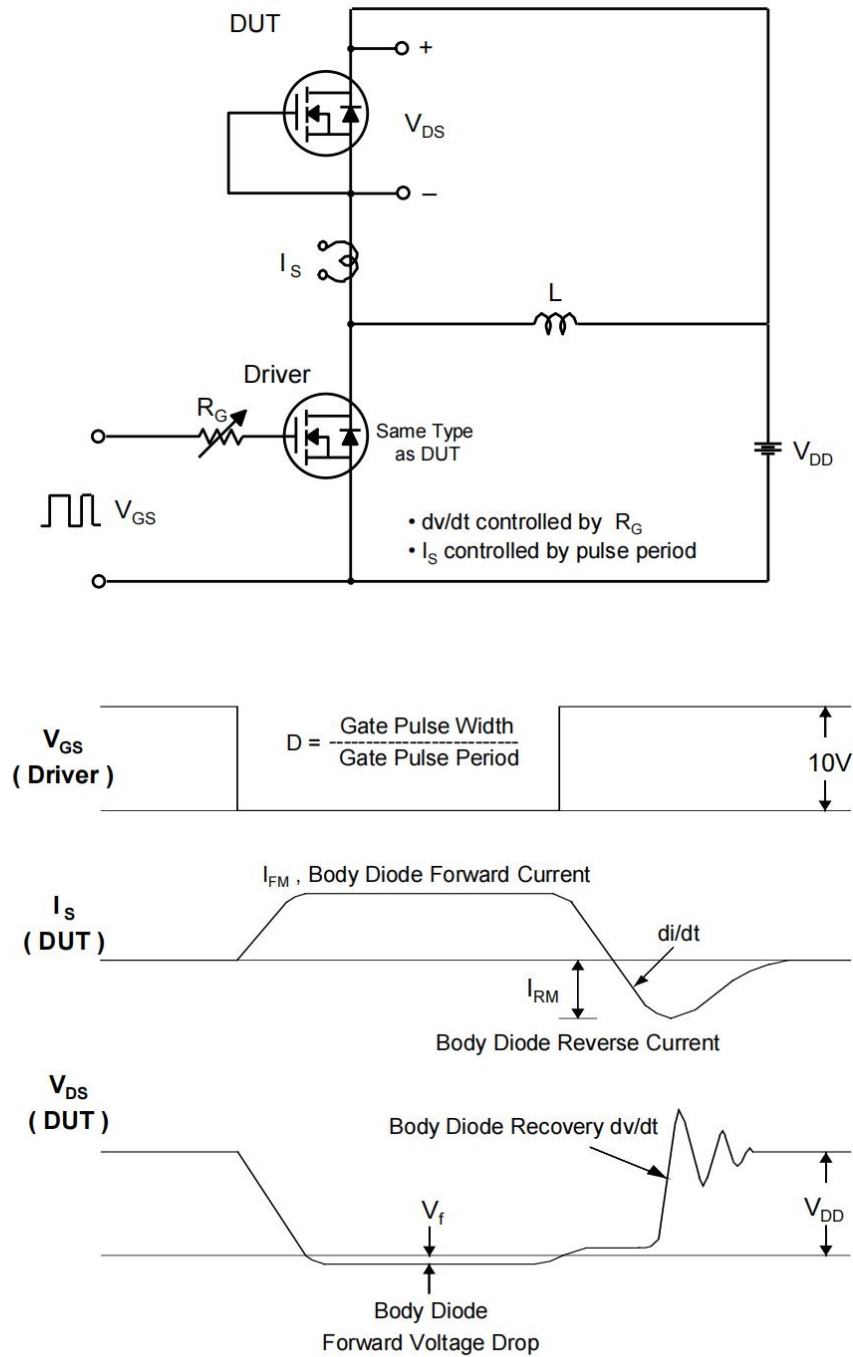


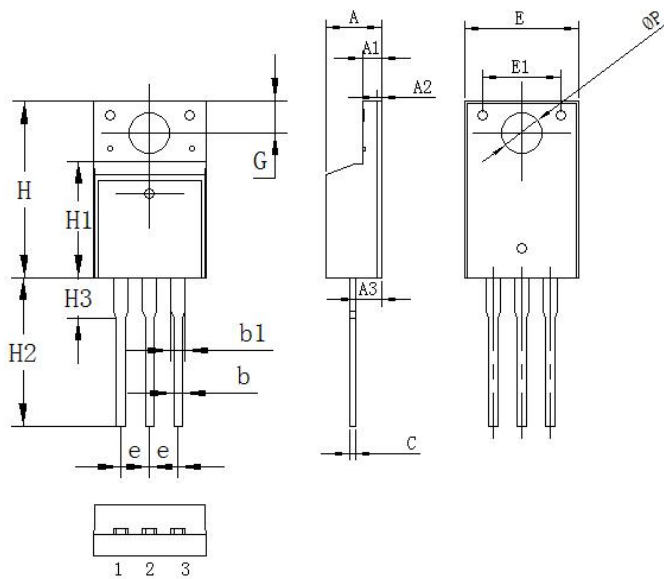
Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Information

TO-220F PACKAGE

基本尺寸



Symbol	单位 mm		
	Min	Nom	Max
A	4.55	4.75	4.95
A1	2.40	2.60	2.80
A2	0.40	0.60	0.80
A3	2.10	2.30	2.50
b1	1.10	1.30	1.50
b	0.60	0.80	1.00
c	0.42	0.50	0.58
e	2.34	2.54	2.74
E	9.9	10.1	10.3
E1	6.8	7	7.2
H	15.8	16.0	16.2
H1	9.10	9.30	9.50
H2	12.5	13.0	13.5
H3	3.10	3.30	3.50
G	3.00	3.20	3.40
ΦP	3.00	3.20	3.40

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